

<b>Notice of References Cited</b>	Application/Control No. 10/800,397	Applicant(s)/Patent Under Reexamination FLESCH ET AL.	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,772,195	08-2004	Hatlelid et al.	709/204
*	B	US-6,795,972	09-2004	Rovira, Luis A.	725/40
*	C	US-7,269,632	09-2007	Edeker et al.	709/217
*	D	US-6,442,432	08-2002	Lee, Michael Thomas	607/59
*	E	US-6,049,341	04-2000	Mitchell et al.	345/473
*	F	US-6,925,495	08-2005	Hegde et al.	709/223
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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